Search Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/845,382	HAYASHI ET AL.	
Examiner	Art Unit	
Kimphung Nguyen	2629	

SEARCHED			
Class	Subclass	Date	Examiner
345	427-428	8/15/2007	KN
345	698	8/15/2007	KN
345	763-764	8/15/2007	· KN
345	836-838	8/15/2007	KN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
East search	8/15/2007	KN
Inventor name	8/15/2007	KN
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